

Joseph A. Spetrini to Robert S. LaRussa on file in the public file of the Central Records Unit, Room B-099 of the Department of Commerce).

This extension is in accordance with section 751(a)(3)(A) of the Tariff Act of 1930, as amended by the URAA (19 U.S.C. 1675(a)(3)(A)).

Dated: May 9, 1997.

Roland MacDonald,

*Acting Deputy Assistant Secretary,
Enforcement Group III.*

[FR Doc. 97-13059 Filed 5-16-97; 8:45 am]

BILLING CODE 3510-DS-M

DEPARTMENT OF COMMERCE

International Trade Administration

[A-533-808]

Certain Stainless Steel Wire Rod From India; Extension of Time Limit of Antidumping Duty Administrative Review

AGENCY: Import Administration, International Trade Administration, Department of Commerce.

ACTION: Notice of extension of time limit of new shipper antidumping duty administrative review.

SUMMARY: The Department of Commerce (the Department) is extending the time limit for the final results in the new shipper administrative review of the antidumping duty order on certain stainless steel wire rod from India, covering the period January 1, 1996 through June 30, 1996, because the review is extraordinarily complicated. **EFFECTIVE DATE:** May 19, 1997.

FOR FURTHER INFORMATION CONTACT: Donald Little or Maureen Flannery, Import Administration, International Trade Administration, U.S. Department of Commerce, 14th Street and Constitution Avenue, N.W., Washington, D.C. 20230; telephone: (202) 482-4733.

SUPPLEMENTARY INFORMATION:

Background

On February 11, 1997, the Department published in the **Federal Register** the preliminary results of this review (see *Certain Stainless Steel Wire Rod From India; Preliminary Results of New Shipper Antidumping Duty Administrative Review*, 62 FR 6171). The review covers the period January 1, 1996, through June 30, 1996. We have determined that this review is extraordinarily complicated within the meaning of section 751(a)(2)(B)(iv) of the Act (see Memorandum from Joseph A. Spetrini to Robert S. LaRussa,

Extension of Time Limits for New Shipper Antidumping Duty Administrative Review of Stainless Steel Wire Rod From India, May 7, 1997). Therefore, in accordance with that section, the Department is extending the time limits for the final results to July 11, 1997. This extension is in accordance with section 751(a)(2)(B)(iv) of the Act.

Dated: May 7, 1997.

Roland L. MacDonald,

*Acting Deputy Assistant Secretary, AD/CVD
Enforcement Group III.*

[FR Doc. 97-13056 Filed 5-16-97; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

Duke University; Notice of Decision on Application for Duty-Free Entry of Scientific Instrument

This decision is made pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Docket Number: 97-021. **Applicant:** Duke University, Durham, NC 27708. **Instrument:** ICP Mass Spectrometer, Model PlasmaQuad 3. **Manufacturer:** VG Elemental, United Kingdom. **Intended Use:** See notice at 62 FR 15657, April 2, 1997.

Comments: None received. **Decision:** Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as it is intended to be used, is being manufactured in the United States. **Reasons:** The foreign instrument provides analysis of trace elements at less than part per trillion abundance levels with a precision of $\pm 2.0\%$. This capability is pertinent to the applicant's intended purposes and we know of no other instrument or apparatus of equivalent scientific value to the foreign instrument which is being manufactured in the United States.

Frank W. Creel,

Director, Statutory Import Programs Staff.

[FR Doc. 97-13054 Filed 5-16-97; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

Skidmore College; Notice of Decision on Application for Duty-Free Entry of Scientific Instrument

This decision is made pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5:00 p.m. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Docket Number: 97-026. **Applicant:** Skidmore College, Saratoga Springs, NY 12866. **Instrument:** Electron Microscope with Accessories, Model JEM-1010. **Manufacturer:** JEOL, Ltd., Japan. **Intended Use:** See notice at 62 FR 17783, April 11, 1997. **Order Date:** January 31, 1997.

Comments: None received. **Decision:** Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as the instrument is intended to be used, was being manufactured in the United States at the time the instrument was ordered. **Reasons:** The foreign instrument is a conventional transmission electron microscope (CTEM) and is intended for research or scientific educational uses requiring a CTEM. We know of no CTEM, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of the instrument.

Frank W. Creel,

Director, Statutory Import Programs Staff.

[FR Doc. 97-13053 Filed 5-16-97; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S.

Department of Commerce, Washington, D.C. 20230. Applications may be examined between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th Street and Constitution Avenue, N.W., Washington, D.C.

Docket Number: 97-031. Applicant: University of Illinois at Chicago, Research Resources Center, 901 S. Wolcott Avenue, Chicago, IL 60612-7341. **Instrument:** Electron Microscope, Model JEM-1220. **Manufacturer:** JEOL, Ltd., Japan. **Intended Use:** The article is intended to be used for studies of the molecular architecture of tissues, cells and isolated molecules obtained as part of the experimental data derived from biomedical research projects. The experiments conducted will involve determining structural alterations in cells during different physiological activities and in pathological states. In addition, the instrument will be used for training Ph.D. candidates, postdoctoral fellows and staff in the biomedical field.

Application accepted by Commissioner of Customs: April 22, 1997.

Docket Number: 97-032. Applicant: University of Illinois at Chicago, Research Resources Center, 901 S. Wolcott Avenue, Chicago, IL 60612-7341. **Instrument:** Electron Microscope, Model JEM-3010. **Manufacturer:** JEOL, Ltd., Japan. **Intended Use:** The instrument will be used for studies of minerals, mineral analogs, materials related to industrial processes, sample interfaces, metals and glass phases of different compounds. **Experiments will include:** (1) Utilizing image processing and electron diffraction patterns to locate electron densities and (2) examining texture, structural alterations, phase transformation, twinning, polytypism, domains, precipitates, exsolution, deformation defects on microstructure and plasticity, and similar phenomena and processes. In addition, the instrument will be used for training Ph.D. candidates and post-doctoral fellows. **Application accepted by Commissioner of Customs:** April 22, 1997.

Docket Number: 97-033. Applicant: Lamont-Doherty Earth Observatory of Columbia University, Rte 9W, Palisades, NY 10964. **Instrument:** ICP Mass Spectrometer, Model Plasma 54. **Manufacturer:** VG Elemental, United Kingdom. **Intended Use:** The instrument will be used for studies of the elemental abundance and isotopic composition of naturally occurring samples, including coral, shell sediments, rocks and natural waters in order to precisely determine the age of the material. **Application accepted by Commissioner of Customs:** April 24, 1997.

Docket Number: 97-037. Applicant: University of Illinois at Urbana-Champaign, Purchasing Division, 506 South Wright Street, 207 Henry Administration Building, Urbana, IL 61801. **Instrument:** UHV Evaporators, Models EFM3 and EFM4. **Manufacturer:** Focus GmbH, Germany. **Intended Use:** The article is intended to be used on a growth chamber attached to a Low-Energy Electron Microscope. The completed instrument will be used for a variety of studies on the mechanisms of growth of thin films. In particular, there will be studies of magnetic multilayer materials, of the effect of surface steps on film growth and of a technique called convergent beam diffraction, which has not been applied to low energy electrons in the past. **Application accepted by Commissioner of Customs:** April 30, 1997.

Frank W. Creel,

Director, Statutory Import Programs Staff.

[FR Doc. 97-13052 Filed 5-17-97; 8:45 am]

BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

International Trade Administration

University of California, San Diego, et al., Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5:00 p.m. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, N.W., Washington, D.C.

Comments: None received. **Decision:** Approved. No instrument of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, is being manufactured in the United States.

Docket Numbers: 96-146 and 97-001. **Applicant:** University of California, San Diego, San Diego, CA 92121. **Instrument:** (10) Directional Waverider Buoys. **Manufacturer:** Datawell, BV, The Netherlands. **Intended Use:** See notices at 62 FR 6215, February 11, 1997 and 62 FR 8928, February 27, 1997. **Reasons:** The foreign instruments provide: (1) more reliable wave direction estimates at frequencies under 1.0 Hz and over 3.0 Hz with less variability within that range and (2) better wave spread estimates than comparable domestic equipment. **Advice received from:** Two

domestic manufacturers of similar instruments, April 23, 1997.

Docket Number: 97-015. Applicant: North Carolina State University, Raleigh, NC 27695-7212. **Instrument:** Photoelectron Emission Microscope. **Manufacturer:** ELMITEC, Germany. **Intended Use:** See notice at 62 FR 10543, March 7, 1997. **Reasons:** The foreign instrument provides a theoretical resolution of 10 nm for photoelectron imaging of crystal growth processes. **Advice received from:** National Institute of Standards and Technology, April 25, 1997.

Docket Number: 97-016. Applicant: Duke University, Durham, NC 27708-0319. **Instrument:** Interferometer. **Manufacturer:** SF SDB "Granat", C.I.S. **Intended Use:** See notice at 62 CF 13600, March 21, 1997. **Reasons:** The foreign instrument provides: (1) multipass operation for optional filtering and (2) demonstrated quality mirror coatings for use with a free electron laser. **Advice received from:** National Institute of Standards and Technology, April 25, 1997.

Docket Number: 97-023. Applicant: Wayne State University, Detroit, MI 48202. **Instrument:** Optical Biosensor with Accessories, Model BIOS-1. **Manufacturer:** Artificial Sensing Instruments, Switzerland. **Intended Use:** See notice at 62 FR 15657, April 2, 1997. **Reasons:** The foreign instrument provides label-free detection of biomolecular interaction to measure the rate of deposition of protein molecules from a solution onto a solid substrate. **Advice received from:** National Institutes of Health, March 19, 1997.

Docket Number: 97-027. Applicant: New Mexico Institute of Mining and Technology, Socorro, NM 87801. **Instrument:** Electron Microprobe, Model SX 100. **Manufacturer:** Cameca, France. **Intended Use:** See notice at 62 FR 15658, April 2, 1997. **Reasons:** The foreign instrument provides characterization of elemental composition and structure in surfaces with resolution down to 1 μ m. **Advice received from:** National Institute of Standards and Technology, July 26, 1996 (comparable case).

Docket Number: 97-028. Applicant: Rutgers University, Piscataway, NJ 08855-6999. **Instrument:** ICP Mass Spectrometer, Model Element. **Manufacturer:** Finnigan MAT, Germany. **Intended Use:** See notice at 62 FR 15658, April 2, 1997. **Reasons:** The foreign instrument provides a magnetic sector mass analyzer with a resolution of 7500 to minimize molecular ion and isobaric interference and determination of transition row metals without hindrance from the occurrence of